

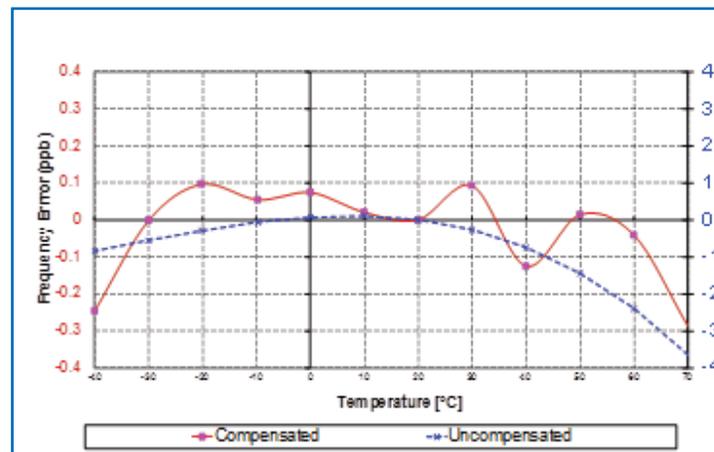
# Coefficient Corrected Oscillator - CCXO

## Introduction

The Coefficient Corrected Oscillator (CCXO) contains a high-stability ovenized crystal oscillator and an I<sup>2</sup>C interface that communicates with temperature and current sensors, and an onboard EEPROM. The interface enables the customer to improve upon the already exceptional stability of the oscillator.

## Definition

Advances in quartz resonators and single-oven control circuits have enabled the mass production of oven controlled crystal oscillators (OCXOs) that are capable of achieving ageing rates of 0.06 ppb/day and temperature stabilities of 0.4 ppb over a commercial temperature range. These stabilities can be further enhanced with the use of commercially available environmental sensors and microprocessors. Vectron's MX series oscillators embed the digital electronics inside the oscillator housing, and microprocessor corrected stabilities to 0.1 ppb have been achieved using this approach. The graph below shows an OCXO with 4 ppb temperature stability that has been corrected to less than 0.3 ppb using a microprocessor.



**Figure 1** – Microprocessor corrected OCXO (red trace) with ~ 10 x improvement from the uncompensated results (blue trace).

For many applications the onboard microprocessor corrected approach is sufficient; however, in some applications customers achieve better results by performing the microprocessor corrections themselves. For these applications, Vectron provides our “Coefficient Corrected Oscillators” (CCXO) series. In addition, incorporating CCXO in a system may result in total lower bill of material costs if the customer already has a microprocessor in the end application.

A CCXO enables the customer to perform microprocessor correction through the use of an I<sup>2</sup>C interface. Through the interface, customers can access on board environmental sensors, digitally control the frequency, and access test information stored in the EEPROM. Each individual oscillator is characterized in a temperature chamber, and the values of the frequency error, temperature sensor, and the current sensor at each test temperature are stored in the EEPROM. The frequency error and temperature sensor results are used to generate the coefficients of the polynomial function

$$F(T) = A_4 T^4 + A_3 T^3 + A_2 T^2 + A_1 T + A_0$$

where F is the frequency error and T is the temperature sensor value. These coefficients are then stored in the EEPROM.

| Chamber Temperature | Temperature Sensor Reading | Frequency Stability | Current Sensor Reading |
|---------------------|----------------------------|---------------------|------------------------|
| -40                 | 126                        | -0.432342           | 1098                   |
| -30                 | 158                        | -0.2187234          | 1021                   |
| -20                 | 190                        | -0.164123           | 944                    |
| -10                 | 222                        | -0.1234545          | 867                    |
| 0                   | 254                        | -0.0976345          | 790                    |
| 10                  | 286                        | -0.0645658          | 713                    |
| 20                  | 318                        | -0.0478988          | 636                    |
| 30                  | 350                        | -0.0211176          | 559                    |
| 40                  | 382                        | 0                   | 482                    |
| 50                  | 414                        | -0.0155449          | 405                    |
| 60                  | 446                        | -0.034322           | 328                    |
| 70                  | 478                        | -0.0573457          | 251                    |
| 80                  | 510                        | -0.0855687          | 174                    |

- A temperature test is performed on each unit.
- The value of the onboard temperature and current sensors, and frequency error of the oscillator at each test temperature is saved to the EEPROM.
- The coefficients of 4th order polynomial frequency vs. temperature are calculated and stored in EEPROM.
- The current and temperature sensors provide real time values via I<sup>2</sup>C during operation.

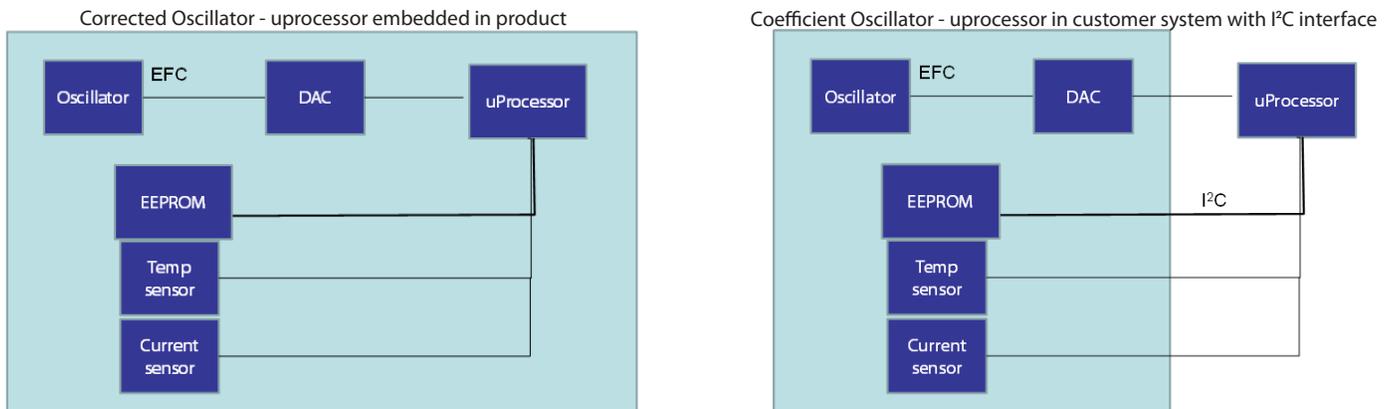
| Coefficient Value |              |
|-------------------|--------------|
| A0                | -2.02214518  |
| A1                | 0.022202701  |
| A2                | -9.63397E-05 |
| A3                | 1.89217E-07  |
| A4                | 1.39561E-10  |

$$F(T) = A_0T^0 + A_1T^1 + A_2T^2 + A_3T^3 + A_4T^4$$

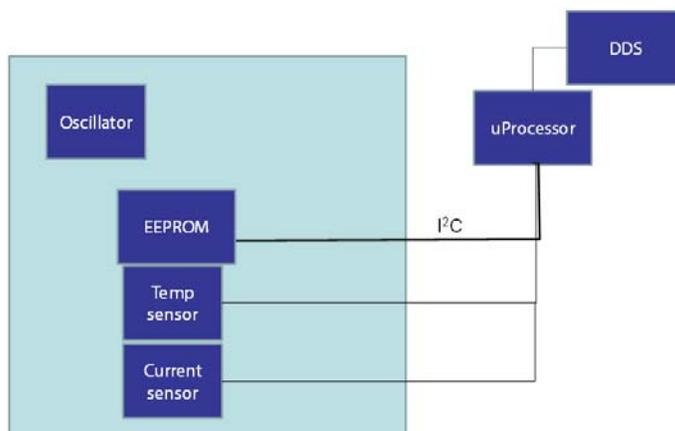
**Figure 2** – Example of data stored in EEPROM.

During use in an application, the customer steers the frequency of the oscillator with the I<sup>2</sup>C interface to address an onboard DAC. Alternatively the customer may use the F(T) information to steer a DDS and use a fixed frequency oscillator.

The block diagrams and table below illustrate the implementation and the differences between a corrected and a coefficient corrected oscillator.



**Figure 3** – Block diagrams of a coefficient and corrected oscillator. In a corrected oscillator the microprocessor is embedded in the OCXO.



**Figure 4** – Alternate configuration with DDS and fixed frequency oscillator for improved stability.

| Corrected Oscillators<br>(MX series products)                     | Coefficients for Correction<br>(MD-xx3 series products)            |
|---|--|
| <b>Pros</b>   |  |
| Minimal implementation effort by customers                        | Fewer correlation issues   |
| Best stability shipped from factory                               | allows customer additional sensing information into the oscillator |
|   | Temperature  |
|   | Current  |
|   | Anything that has an I <sup>2</sup> C sensor available             |
|   | Customer can compensate for other effects                          |
| <b>Cons</b>   |  |
| Frequency vs Temperature curve is difficult for customer to model | Higher implementation effort at customer                           |
| Correlation issues  |  |
| Airflow may affect correlation                                    |  |

The coefficient corrected oscillator approach requires more design effort at the customer to implement, but provides the customer with more control of the oscillator in the end application. In addition to the frequency versus-temperature benefits, the current sensor provides insight into the oscillator that can be used for several purposes. In an OCXO, an oven is used to keep the crystal at a constant temperature while the ambient environmental temperature is varied.

The current exhibits the following behavior:

- The steady-state oven current consumption varies inversely to the temperature.
- The current consumption at a fixed temperature increase as airflow is increased due to additional power required to stabilize the oven.
- Increased airflow may alter the measured frequency vs temperature performance.
- When the ambient temperature is varied, a transient current response occurs prior to reaching the new steady-state value.

The behavior can provide valuable insight into the oscillator allowing the customer to utilize the current sensor as an indicator for:

- Thermal stabilization
- Degradation of the F(T) equation if current is not similar to current stored in EEPROM for temperature

Ultimately this data can be used to create a new two independent variable relation F(I,T), where F is the frequency error, I is the current sensor value, and T is the temperature sensor value.

## Conclusion

the CCXOs (MD-xx3 series) afford the customer the opportunity to gain valuable insight to the oscillator performance, and ultimately to enhance the performance in their end application at a reduced cost. The solution does require more upfront effort than an off-the-shelf corrected oscillator, but provides a path for improved performance.

### For Additional Information, Please Contact

#### USA:

Vectron International  
267 Lowell Road, Unit 102  
Hudson, NH 03051  
Tel: 1.888.328.7661  
Fax: 1.888.329.8328

#### Europe:

Vectron International  
Landstrasse, D-74924  
Neckarbischofsheim, Germany  
Tel: +49 (0) 7268.8010  
Fax: +49 (0) 7268.801281

#### Asia:

Vectron International  
68 Yin Cheng Road(C), 22nd Floor,  
One LuJiaZui  
Pudong, Shanghai 200120, China  
Tel: +86 21 6194.6886  
Fax: +86 21 6194.6699

#### Disclaimer

Vectron International reserves the right to make changes to the product(s) and or information contained herein without notice. No liability is assumed as a result of their use or application. No rights under any patent accompany the sale of any such product(s) or information.